## Notice of References Cited

Application/Control No. 10/634,392	Reexamination	Applicant(s)/Patent Under Reexamination AN, CHI WOOK		
Examiner	Art Unit			
Jason M Han	2875	Page 1 of 3		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
,	Α	US-2,346,988	04-1944	NOEL EDWARD B	355/88
	В	US-3,538,322	11-1970	ARSEM ALVAN DONALD	362/19
	С	US-4,074,124	02-1978	Maute et al.	362/217
	D	US-4,229,783	10-1980	Eberhardt, Noel	362/352
	E	US-4,287,531	09-1981	Mitamura et al.	348/813
	F	US-4,714,983	12-1987	Lang, Warren R.	362/27
	G	US-4,739,454	04-1988	Federgreen, Richard	362/133
	Н	US-4,855,818	08-1989	Morimoto et al.	358/512
	1	US-4,899,175	02-1990	Harada et al.	347/238
	J	US-4,907,862	03-1990	Suntola, Tuomo S.	349/61
	к	US-4,920,410	04-1990	Tomii et al.	348/796
	L	US-4,991,070	02-1991	Stob, Henry R.	362/223
T	М	US-5,038,259	08-1991	Katoh et al.	. 362/256

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z	JP63200102	08-1988	Japan	Ito, Isao	G02B 6/00
	0	JP04147127	05-1992	Japan	Imai, Masaaki	G03B 27/10
	Р	JP2000111909	04-2000	Japan	Shiotani, Yasushi et al.	G02F 1/1335
	a					
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	S					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

## Notice of References Cited Application/Control No. 10/634,392 Examiner Jason M Han Applicant(s)/Patent Under Reexamination AN, CHI WOOK Page 2 of 3

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,040,101	08-1991	Aspenwall, John E.	362/125
	В	US-5,477,423	12-1995	Fredriksz et al.	362/31
	С	US-5,510,965	04-1996	Teakell, Joe F.	362/223
	D	US-5,889,366	03-1999	Yokokawa et al.	313/607
	Ē	US-6,002,452	12-1999	Morgan, Dan	348/742
	F	US-6,031,330	02-2000	Yoshida et al.	313/607
	G	US-6,186,649	02-2001	Zou et al.	362/347
	Н	US-6,232,963	05-2001	Tew et al.	345/204
	1	US-6,292,594	09-2001	Iwai, Kenichi	382/298
	J	US-6,369,523	04-2002	Matsuura et al.	315/291
	К	US-2002/0057238	05-2002	Nitta et al.	345/87
	L	US-6,535,187	03-2003	Wood, Lawson A.	345/84
	М	US-6,573,882	06-2003	Takabayashi, Hiroshi	345/102

#### **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination AN, CHI WOOK Examiner | Art Unit | Page 3 of 3

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,583,579	06-2003	Tsumura, Toshiyuki	315/169.3
	В	US-6,614,185	09-2003	Nishimura et al.	313/607
	С	US-6,693,619	02-2004	Miura et al.	345/102
	D	US-6,791,527	09-2004	Yoshinaga et al.	345/102
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	l	US-			
	J	US-			
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## FOREIGN PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.